



## Linear Component Parameters

(MIL-STD-883G, Method 2012.7)

This procedure is nondestructive and it detects defects within the sealed case, especially those resulting from the sealing process and internal defects such as foreign objects, improper interconnecting wires, and voids in the die attach material or in the glass when glass seals are used.

<b>Voltage Comparators</b>	<b>Voltage Follower</b>	<b>Current Mirror</b>	<b>Fixed Vol. Regulator</b>
+I	+Icc	Ido+	Iq+
-I	-Icc	Idg+	Iq-
Vos	Vos	GBWP	Vo/m
GAIN	Ib+	Vol	Vo/M
Ib+	VosRs	Voh	Vref/m
Ib-	VosBAL	Ai/m	Vref/mM
Ios	GAIN	Ai/m	Rout
Ibias	+PSRR	Ib-	Isd
VosRs	-PSRR	Aol	Ipk/m
Vsi	Rout	PSRR	Ipk/M
Vsh	+Vout	Isoht	Vin/m
Isl	-Vout	Isohl	Vin/M
+Vout	--	Isink	Vdf/m
Vsat	--	--	Vdf/M
Isink	--	--	BAL

<b>Adjustable Voltage Reg.</b>	<b>Volt. Regulator</b>	<b>ADC &amp; DAC</b>	<b>Opto Coupler</b>
Iq+ Iq- Vref/m Vref/M Rout Vout/m Vout/M Isd Isc/m Isc/M Vin/m Vin/M Vdf/m Vdf/M BAL -- --	Iq+ Iq- Iref/m Iref/M Rout Vref/m Vref/M Isc/m Isc/M Vin/m Vin/M Vdif/m Vdif/m -- -- -- --	+Icc -Icc Ic VREF ZERO 1 GAIN 1 ZERO 2 GAIN 2 ZERO 3 GAIN 3 ZERO 4 GAIN 4 Lin DLin dFS+ dFD	ICEO VF VCESAT CTR BVCEO BVECO BVCBO BVR ICBO IR -- -- -- -- -- --
<b>Timer</b>  Icc+ Icc- Vol Voh Vcl Vcl Vt It Ir Vr Idis Ith -- -- -- -- --			